



National Standards Authority of Ireland

IRISH STANDARD

I.S. EN 61747-5:1999

ICS 31.120

**LIQUID CRYSTAL AND SOLID-STATE DISPLAY
DEVICES. PART 5: ENVIRONMENTAL,
ENDURANCE AND MECHANICAL TEST
METHODS
(IEC 61747-5:1998)**

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EN 61747-5

September 1998

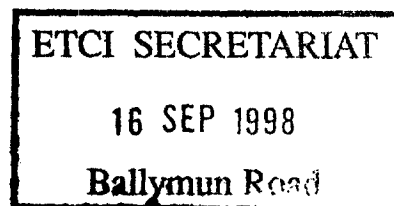
ICS 31.120

English version

Liquid crystal and solid-state display devices
Part 5: Environmental, endurance and mechanical test methods
(IEC 61747-5:1998)

Dispositifs d'affichage à cristaux
liquides et à semiconducteurs
Partie 5: Méthodes d'essais
d'environnement, d'endurance et
mécaniques
(CEI 61747-5:1998)

Flüssigkristall- und Halbleiter-
Anzeige-Bauelemente
Teil 5: Umwelt-, Lebensdauer-
und mechanische Prüfverfahren
(IEC 61747-5:1998)



This European Standard was approved by CENELEC on 1998-08-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 47C/203/FDIS, future edition 1 of IEC 61747-5, prepared by SC 47C, Optoelectronic, display and imaging devices, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61747-5 on 1998-08-01.

The following dates were fixed:

- latest date by which the EN has to be implemented
at national level by publication of an identical
national standard or by endorsement (dop) 1999-05-01
- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2001-05-01

Annexes designated "normative" are part of the body of the standard.

Annexes designated "informative" are given for information only.

In this standard, annex ZA is normative and annex A is informative.

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61747-5:1998 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)**Normative references to international publications
with their corresponding European publications**

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE: When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	1988	Environmental testing Part 1: General and guidance	EN 60068-1 ¹⁾	1994
IEC 60068-2-1	1990	Part 2: Tests - Tests A: Cold	EN 60068-2-1	1993
IEC 60068-2-2	1974	Part 2: Tests - Test B: Dry heat	EN 60068-2-2 ²⁾	1993
IEC 60068-2-3	1969	Part 2: Tests - Test Ca: Damp heat, steady state	HD 323.2.3 S2 ³⁾	1987
IEC 60068-2-5	1975	Part 2: Tests - Test Sa: Simulated solar radiation at ground level	HD 323.2.5 S1	1988
IEC 60068-2-6 + corr. March	1995 1995	Part 2: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	1995
IEC 60068-2-7	1983	Part 2: Tests - Test Ga and guidance: Acceleration, steady state	EN 60068-2-7 ⁴⁾	1993
IEC 60068-2-13	1983	Part 2: Tests - Test M: Low air pressure	HD 323.2.13 S1	1987
IEC 60068-2-14	1984	Part 2: Tests - Test N: Change of temperature	HD 323.2.14 S2 ⁵⁾	1987
IEC 60068-2-20	1979	Part 2: Tests - Test T: Soldering	HD 323.2.20 S3 ⁶⁾	1988
IEC 60068-2-21	1983	Part 2: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21 ⁷⁾	1997

1) EN 60068-1 includes the corrigendum October 1988 and A1:1992 to IEC 60068-1.

2) EN 60068-2-2 includes supplement A:1976 to IEC 60068-2-2.

3) HD 323.2.3 S2 includes A1:1984 to IEC 60068-2-3.

4) EN 60068-2-7 includes A1:1986 to IEC 60068-2-7.

5) HD 323.2.14 S2 includes A1:1986 to IEC 60068-2-14.

6) HD 323.2.20 S3 includes A2:1987 to IEC 60068-2-20.

7) EN 60068-2-21 includes the corrigendum November 1991 and A1:1985 to IEC 60068-2-21.

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-27	1987	Part 2: Tests - Test Ea and guidance: Shock	EN 60068-2-27	1993
IEC 60068-2-30	1980	Part 2: Tests - Test Db and guidance: Damp heat, cyclic (12 + 12 hour cycle)	HD 323.2.30 S3 ⁸⁾	1988
IEC 60068-2-38	1974	Part 2: Tests - Test Z/AD: Composite temperature/humidity cyclic test	HD 323.2.38 S1	1988
IEC 60068-2-45	1980	Part 2: Tests - Test Xa and guidance: Immersion in cleaning solvents	EN 60068-2-45	1992
IEC 60747-1	1983	Semiconductor devices - Discrete devices Part 1: General	-	-
A1	1991		-	-
A2	1993		-	-
A3	1996		-	-
IEC 60747-5	1984	Part 5: Optoelectronic devices	-	-
A1	1994		-	-
A2	1995		-	-
IEC 60748-1	1984	Semiconductors devices - Integrated circuits Part 1: General	-	-
IEC 60749	1996	Semiconductor devices - Mechanical and climatic test methods	-	-
IEC 61747	series	Liquid crystal and solid-state display devices	-	-

8) HD 323.2.30 S3 includes A1:1985 to IEC 60068-2-30.

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